


Search Notes 	Application/Control No. 10675529	Applicant(s)/Patent Under Reexamination HEIN, JERRELL
	Examiner Franklin, Richard	Art Unit 2181

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search	1/19/07	RBF
326/51; 327/291,298; 331/1r,18,107r,108c,108r,158,177r,182,183; 710/1,8,14; 713/600,601; 716/12,16,17; 726/34-36 (Limited EAST Text Search)	1/19/07	RBF
David Martinez (Patent Examiner; Art Unit 2181; 710/1-74)	1/11/07	RBF
Niketa Patel (Patent Examiner; Art Unit 2181; 710/1-74)	1/11/07	RBF
Josh Schneider (Patent Examiner; Art Unit 2182; 710/1-74)	1/11/07	RBF
PLUS 2.0 Search	1/18/07	RBF
Inventor Name Search	1/18/07	RBF
Alan Chen (Patent Examiner; AU 2182; 710/1-74)	1/19/07	RBF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner